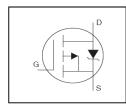


AUTOMOTIVE GRADE

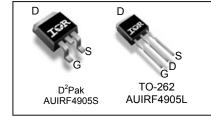
AUIRF4905S AUIRF4905L

Features

- Advanced Planar Technology
- P-Channel MOSFET
- Low On-Resistance
- 150°C Operating Temperature
- Fast Switching
- · Repetitive Avalanche Allowed up to Tjmax
- Lead-Free, RoHS Compliant
- Automotive Qualified *



HEXFE	HEXFET Power MOSFET		
V _{DSS}	-55V		
R _{DS(on)} max.	20mΩ		
I _D (Silicon Limited)	-70A		
D (Package Limited)	-42A		



G	D	S
Gate	Drain	Source

Description

Specifically designed for Automotive applications, this cellular design of HEXFET® Power MOSFETs utilizes the latest processing techniques to achieve low on-resistance per silicon area. This benefit combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in Automotive and a wide variety of other applications.

Base next number	Dookogo Typo	Standard Pack	,	Orderable Part Number
Base part number	Package Type	Form	Quantity	Orderable Part Number
AUIRF4905L	TO-262	Tube	50	AUIRF4905L
ALUDE 400EC	D²-Pak	Tube	50	AUIRF4905S
AUIRF4905S	D -Pak	Tape and Reel Left	800	AUIRF4905STRL

Absolute Maximum Ratings

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only; and functional operation of the device at these or any other condition beyond those indicated in the specifications is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability. The thermal resistance and power dissipation ratings are measured under board mounted and still air conditions. Ambient temperature (TA) is 25°C, unless otherwise specified.

Symbol	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	-70	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)	-44	1 ,
I_D @ T_C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited)	-42	A
I _{DM}	Pulsed Drain Current ①	-280	
P _D @T _C = 25°C	Maximum Power Dissipation	170	W
	Linear Derating Factor	1.3	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy (Thermally Limited) ②	140	
E _{AS} (tested)	Single Pulse Avalanche Energy Tested Value ®	790	mJ
I _{AR}	Avalanche Current ①	See Fig.15,16, 12a, 12b	Α
E _{AR}	Repetitive Avalanche Energy ①		mJ
T_J	Operating Junction and	-55 to + 150	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

Thermal Resistance

THEITHAI NESISTAI	iice			
Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		0.75	°CAM
R _{e.IA}	Junction-to-Ambient (PCB Mount, steady state) ⑦®		40	°C/W

HEXFET® is a registered trademark of Infineon.

^{*}Qualification standards can be found at www.infineon.com



Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	-55			V	$V_{GS} = 0V, I_{D} = -250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		-0.054		V/°C	Reference to 25°C, I _D = -1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance			20	mΩ	$V_{GS} = -10V, I_D = -42A$ ③
$V_{GS(th)}$	Gate Threshold Voltage	-2.0		-4.0	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$
gfs	Forward Trans conductance	19			S	$V_{DS} = -25V, I_{D} = -42A$
	Drain-to-Source Leakage Current			-25		$V_{DS} = -55V, V_{GS} = 0V$
I _{DSS}	Diani-lo-Source Leakage Current			-250	μA	$V_{DS} = -44V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			-100	- A	$V_{GS} = -20V$
	Gate-to-Source Reverse Leakage			100	nA	V _{GS} = 20V

Dynamic Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

		 	,		
Q_g	Total Gate Charge	 120	180		$I_{D} = -42A$
Q_{gs}	Gate-to-Source Charge	 32		nC	$V_{DS} = -44V$
Q_{gd}	Gate-to-Drain Charge	 53			V _{GS} = -10V3
$t_{d(on)}$	Turn-On Delay Time	 20			$V_{DD} = -28V$
t _r	Rise Time	 99			$I_D = -42A$
$t_{d(off)}$	Turn-Off Delay Time	 51		ns	$R_G = 2.6\Omega$,
t _f	Fall Time	 64			V _{GS} = -10V ③
L _D	Internal Drain Inductance	 4.5		nH	Between lead, 6mm (0.25in.)
L _S	Internal Source Inductance	 7.5		ПП	from package and center of die contact
C _{iss}	Input Capacitance	 3500			$V_{GS} = 0V$
Coss	Output Capacitance	 1250			$V_{DS} = -25V$
C _{rss}	Reverse Transfer Capacitance	 450			f = 1.0MHz
Coss	Output Capacitance	 4620		pF	$V_{GS} = 0V, V_{DS} = -1.0V f = 1.0MHz$
Coss	Output Capacitance	 940			$V_{GS} = 0V, V_{DS} = -44V f = 1.0MHz$
Coss eff.	Effective Output Capacitance	 1530			$V_{GS} = 0V, V_{DS} = 0V \text{ to -44V } $

Diode Characteristics

21000 011011001001						
	Parameter	Min.	Тур.	Max.	Units	Conditions
	Continuous Source Current			-42		MOSFET symbol
I _S	(Body Diode)			-42		showing the
1	Pulsed Source Current		280	200	A	integral reverse
I _{SM}	(Body Diode) ①				-200	00
V_{SD}	Diode Forward Voltage			-1.3	V	$T_J = 25^{\circ}C, I_S = -42A, V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		61	92	ns	$T_J = 25^{\circ}C$, $I_F = -42A$, $V_{DD} = -28V$
Q_{rr}	Reverse Recovery Charge		150	220	nC	di/dt = 100A/µs ③
t _{on}	Forward Turn-On Time	Intrinsi	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)			

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig.11)
- ② Limited by T_{Jmax} , starting T_J = 25°C, L = 0.16mH, R_G = 25 Ω , I_{AS} = -42A, V_{GS} =-10V. Part not recommended for use above this value.
- \oplus C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.
- $\$ Limited by T_{Jmax} , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.
- © This value determined from sample failure population, starting $T_J = 25^{\circ}C$, L = 0.08mH, $R_G = 25\Omega$, $I_{AS} = 66$ A, $V_{GS} = 10$ V.
- This is applied to D² Pak, When mounted on 1" square PCB (FR-4 or G-10 Material). For recommended footprint and soldering techniques refer to application note #AN-994



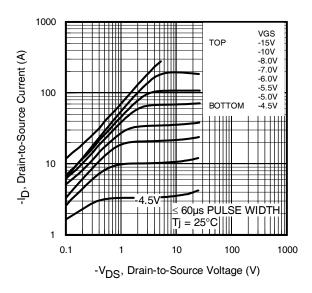


Fig. 1 Typical Output Characteristics

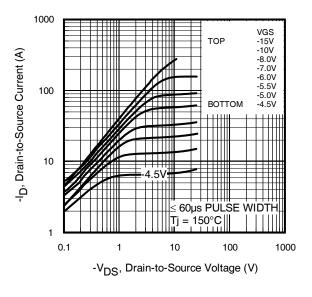


Fig. 2 Typical Output Characteristics

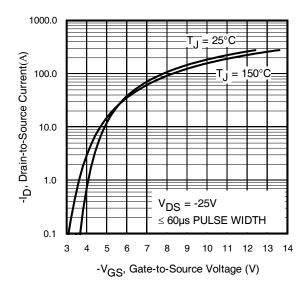


Fig. 3 Typical Transfer Characteristics

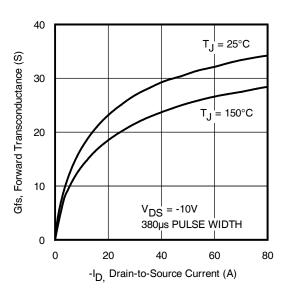


Fig. 4 Typical Forward Trans conductance vs. Drain Current

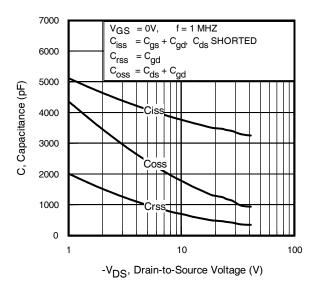


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

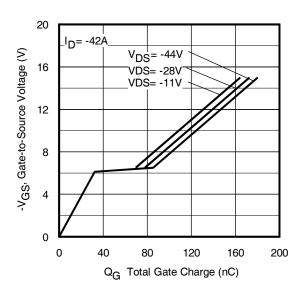


Fig 6. Typical Gate Charge vs. Gate-to-Source Voltage

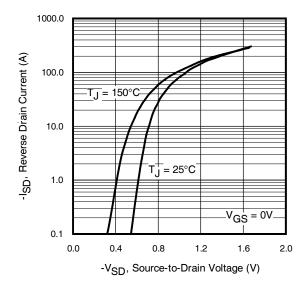


Fig. 7 Typical Source-to-Drain Diode Forward Voltage

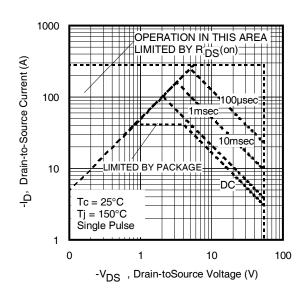


Fig 8. Maximum Safe Operating Area



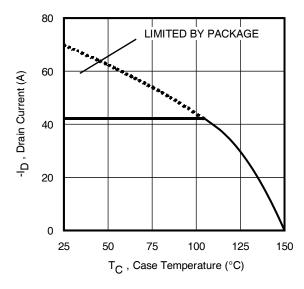


Fig 9. Maximum Drain Current vs. Case Temperature

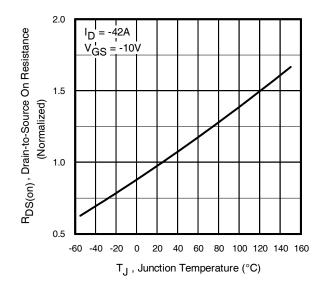


Fig 10. Normalized On-Resistance vs. Temperature

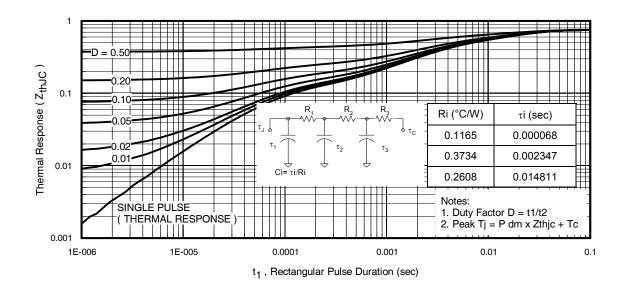


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case



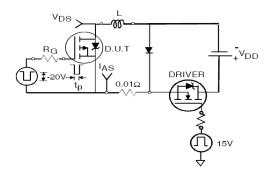


Fig 12a. Unclamped Inductive Test Circuit

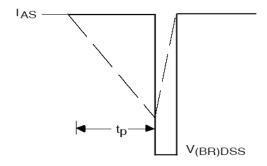


Fig 12b. Unclamped Inductive Waveforms

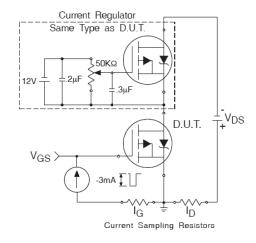


Fig 13a. Gate Charge Test Circuit

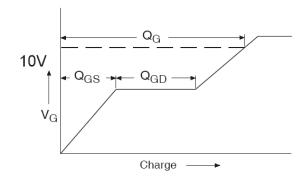


Fig 13b. Gate Charge Waveform

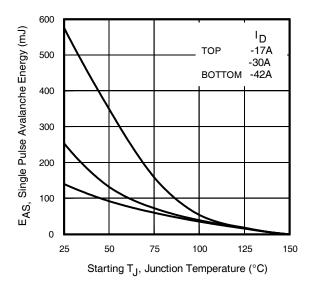


Fig 12c. Maximum Avalanche Energy vs. Drain Current

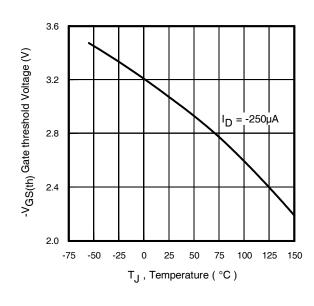


Fig 14. Threshold Voltage vs. Temperature



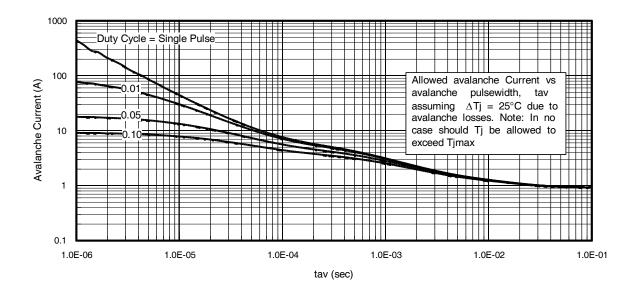
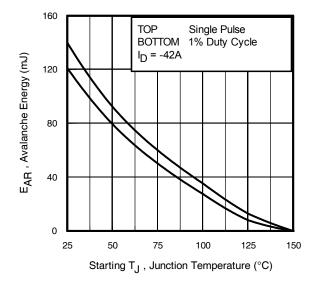


Fig 15. Avalanche Current vs. Pulse width



Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see AN-1005 at www.infineon.com)

- Avalanche failures assumption:

 Divisit of the most phanement and failure assume at a term.
 - Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax} . This is validated for every part type.
- 2. Safe operation in Avalanche is allowed as long as Tjmax is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
- 4. PD (ave) = Average power dissipation per single avalanche pulse.
- BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. lav = Allowable avalanche current.
- ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 14, 15).

tav = Average time in avalanche.

D = Duty cycle in avalanche = $t_{av} \cdot f$

ZthJC(D, tav) = Transient thermal resistance, see Figures 13)

$$\begin{split} P_{D \text{ (ave)}} &= 1/2 \text{ (} 1.3 \cdot \text{BV} \cdot \text{I}_{av} \text{)} = \Delta \text{T} / \text{ Z}_{\text{thJC}} \\ \\ I_{av} &= 2\Delta \text{T} / \text{ [} 1.3 \cdot \text{BV} \cdot \text{Z}_{\text{th}} \text{]} \\ \\ E_{AS \text{ (AR)}} &= P_{D \text{ (ave)}} \cdot t_{av} \end{split}$$

Fig 16. Maximum Avalanche Energy vs. Temperature



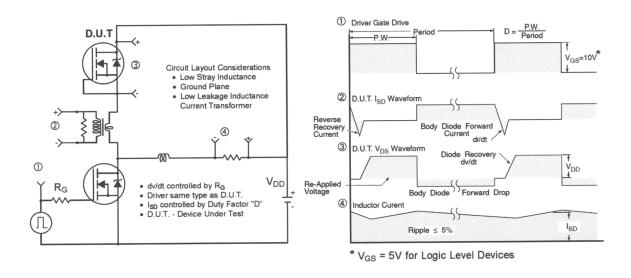


Fig 17. Peak Diode Recovery dv/dt Test Circuit for P-Channel HEXFET® Power MOSFETs

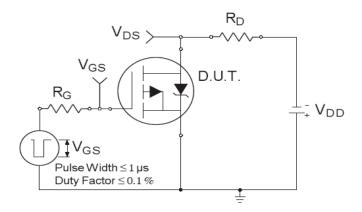


Fig 18a. Switching Time Test Circuit

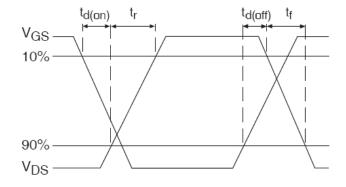
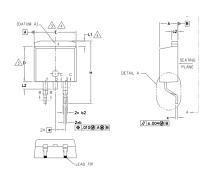
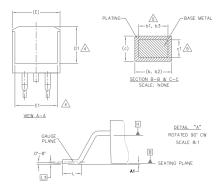


Fig 18b. Switching Time Waveforms



D²Pak (TO-263AB) Package Outline (Dimensions are shown in millimeters (inches))





- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61, 63 AND c1 APPLY TO BASE METAL ONLY.

- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7. CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263AB.

S	DIMENSIONS				
M B	MILLIM	ETERS	RS INCHES		
O L	MIN.	MAX.	MIN.	MAX.	NOTES
А	4.06	4.83	.160	.190	
A1	0.00	0.254	.000	.010	
Ь	0.51	0.99	.020	.039	
ь1	0.51	0.89	.020	.035	5
b2	1.14	1.78	.045	.070	
ь3	1.14	1.73	.045	.068	5
С	0.38	0.74	.015	.029	
с1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270	_	4
E	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245	_	4
е	2.54	BSC	.100	.100 BSC	
Н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	_	1.68	_	.066	4
L2	_	1.78	_	.070	
L3	0.25	BSC	.010	BSC	

LEAD ASSIGNMENTS

DIODES

1.— ANODE (TWO DIE) / OPEN (ONE DIE) 2, 4.— CATHODE 3.— ANODE

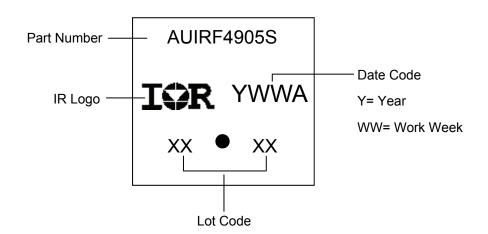
HEXFET

IGBTs, CoPACK

1.- GATE 2, 4.- DRAIN 3.- SOURCE

1.- GATE 2, 4.- COLLECTOR 3.- EMITTER

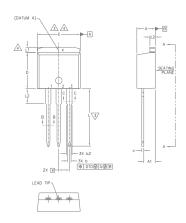
D²Pak (TO-263AB) Part Marking Information

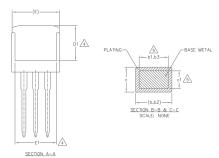


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



TO-262 Package Outline (Dimensions are shown in millimeters (inches)





1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994

2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

O.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY.

4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.

5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.

6. CONTROLLING DIMENSION: INCH.

7.— OUTLINE CONFORM TO JEDEC TO-262 EXCEPT A1(max.), b(min.) AND D1(min.) WHERE DIMENSIONS DERIVED THE ACTUAL PACKAGE OUTLINE.

LEAD ASSIGNMENTS

IGBTs, CoPACK

1.- GATE
2.- COLLECTOR
3.- EMITTER
4.- COLLECTOR

<u>HEXFET</u>

DIODES

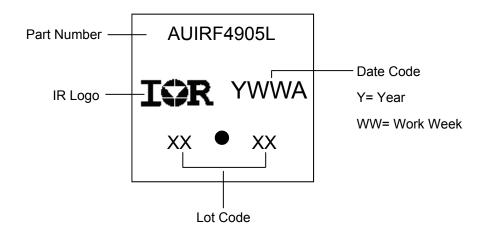
1.- ANODE (TWO DIE) / OPEN (ONE DIE)
2, 4.- CATHODE
3.- ANODE

1.- GATE 2.- DRAIN 3.- SOURCE 4.- DRAIN

JKAIN		
S Y		

S						
Y M		DIMENSIONS				
В	MILLIM	ETERS	INC	HES	O T E S	
0 L	MIN.	MAX.	MIN.	MAX.	S	
А	4.06	4.83	.160	.190		
A1	2.03	3.02	.080	.119		
b	0.51	0.99	.020	.039		
b1	0.51	0.89	.020	.035	5	
b2	1.14	1.78	.045	.070		
b3	1.14	1.73	.045	.068	5	
С	0.38	0.74	.015	.029		
c1	0.38	0.58	.015	.023	5	
c2	1.14	1.65	.045	.065		
D	8.38	9.65	.330	.380	3	
D1	6.86	-	.270	_	4	
E	9.65	10.67	.380	.420	3,4	
E1	6.22	_	.245		4	
е	2.54	BSC	.100	.100 BSC		
L	13.46	14.10	.530	.555		
L1	_	1.65	_	.065	4	
L2	3.56	3.71	.140	.146		

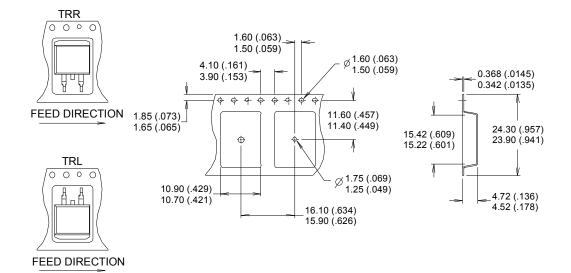
TO-262 Part Marking Information

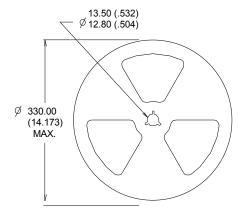


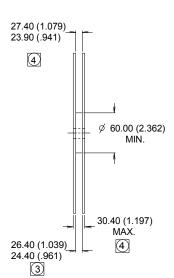
Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



D²Pak (TO-263AB) Tape & Reel Information (Dimensions are shown in millimeters (inches))







NOTES:

- 1. COMFORMS TO EIA-418.
- COMPORMS TO EIA-416.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION MEASURED @ HUB.
- INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



Qualification Information

			Automotive	
		(per AEC-Q101)		
		Comments: This part number(s) passed Automotive qualification. Infineon's		
		Industrial and Consumer qualification level is granted by extension of the higher		
		Automotive level.		
Moisture Sensitivity Level		TO-262 Pak	MSL1	
		D ² -Pak		
ESD	Machine Model	Class M4 (+/- 425V) [†]		
		AEC-Q101-002		
	Human Body Model	Class H2 (+/- 4000V) [†]		
		AEC-Q101-001		
	Charged Device Model	Class C5 (+/- 1125V) [†]		
		AEC-Q101-005		
RoHS Compliant		Yes		

[†] Highest passing voltage.

Revision History

Date	Comments	
11/13/2015	Updated datasheet with corporate template	
11/13/2013	Corrected ordering table on page 1.	

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Mouser Electronics

Authorized Distributor

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AUIRF4905L AUIRF4905S AUIRF4905STRL